

	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/713,047	YUEH, WEN H	SIANG
į	Examiner	Art Unit	
	Duc M. Nguyen	2685	

SEARCHED					
Class	Subclass	Date	Examiner		
455	569.1 556.1 556.2				
	557 558				
	552.1				
	41.1 41.2				
	575.2				
	566 567				
	90.1 90.2				
	66 344				
	346 349	2/13/2006	DN		
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	2/13/2006	DN		